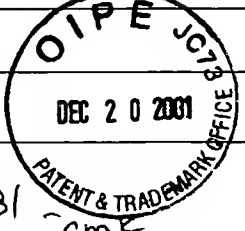


FORM PTO 1449  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY DOCKET NO. <b>DEH009</b>	SERIAL NO. 09/995,662	
	APPLICANT <b>BATEMAN ET AL.</b>		
	FILING DATE NOVEMBER 29, 2001	GROUP N/A 2881	

### U.S. Patent Documents

Examiner Initial	Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate
CMK	5,572,035	11/96	FRANZEN	—	—	—
CMK	6,107,628	08/00	SMITH ET AL.	—	—	—

### Foreign Patent Documents

Examiner Initial	Document Number	Publication Date	Country/Agency	Class	Subclass	Translation	
						Yes	No
CMK	2,302,985	02/97	UK	—	—	✓	
CMK	WO97/49111	12/97	PCT	—	—	✓	
CMK	WO99/38185	07/99	PCT	—	—	✓	
CMK	2,281,405	03/00	CA	—	—	✓	

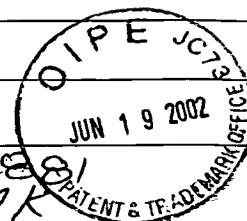
### Other Documents (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)

CMK	Teloy et al., "Integral Cross Sections for Ion-Molecule Reactions. 'I. The Guided Beam Technique'", Chemical Physics, pp.417-427, (1974).
CMK	Gerlich et al., "Ion Trap Studies of Association Processes in Collisions of $\text{Ch}^+$ and $\text{CD}^+$ with $n\text{-H}_2$ , $p\text{-H}_2$ , $\text{D}_2$ , and He at 80 K", The Astrophysical Journal, 347 pp.849-854, 1989.
CMK	Gerlich, "Inhomogeneous RF Fields: A Versatile Tool for the Study of Processes with Slow Ions", Advances in Chemical Physics Series. Vol. 1.XXXII, 1992.
CMK	Shaffer et al., "A Novel Ion Funnel for Focusing Ions at Elevated Pressures", The 45 <sup>th</sup> ASMS Conference on Mass Spectrometry and Allied Topics, (1997).
CMK	Shaffer et al., "A Novel Ion Funnel for Focusing Ions at Elevated Pressure Using Electrospray Ionization Mass Spectrometry", Rapid. Communications in Mass Spectrometry, Vol. 11, pp. 1813-1817 (1997).
CMK	Shaffer et al., "An Ion Funnel Interface for Improved Ion Focusing and Sensitivity Using Electrospray Ionization Mass Spectrometry", Analytical Chemistry, Vol. 70, No. 19, pp. 4111-4119, (1998).
CMK	Shaffer et al., "Characterization of an Improved Electrodynamical Ion Funnel Interface for Electrospray Ionization Mass Spectrometry", Analytical Chemistry, Vol. 71, No. 15, pp. 2957-2964, (1999).
CMK	Tolmachev et al., "Charge Capacity Limitations of Radio Frequency Ion Guides in Their Use for Improved Ion Accumulation and Trapping in Mass Spectrometry", Analytical Chemistry, Vol. 72, No. 5, pp. 970-978, (2000).
CMK	Bailey et al., "Design and Implementation of a New Electrodynamical Ion Funnel", Analytical Chemistry, Vol. 72, No. 10, pp. 2247-2255, (2000).

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Examiner: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; Draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	APPLICANT <b>BATEMAN ET AL.</b>	
	FILING DATE <b>NOVEMBER 29, 2001</b>	GROUP <b>2881</b> N/A <b>CMR</b>



### U.S. Patent Documents

Examiner Initial	Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate
CMR	5,818,055	10/98	FRANZEN	250	292	7/10/1997

### Foreign Patent Documents

Examiner Initial	Document Number	Publication Date	Country/Agency	Class	Subclass	Translation	
						Yes	No
CMR	2,315,364	01/98	UK	—	—	✓	
CMR	113852	04/00	JP	—	—	✓	
CMR	123780	04/00	JP	—	—	✓	

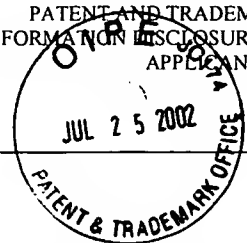
### Other Documents (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)


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	APPLICANT <b>BATEMAN ET AL.</b>	
	FILING DATE <b>NOVEMBER 29, 2001</b>	GROUP <b>2856 2881 -CMK</b>



### U.S. Patent Documents

Examiner Initial	Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate
CMK	2001/0035498	11/01	LI ET AL.	—	—	—

### Foreign Patent Documents

Examiner Initial	Document Number	Publication Date	Country/Agency	Class	Subclass	Translation Yes	Translation No
CMK	98/06481	2/98	WO	—	—	✓	
CMK	11-307040	11/99	JP	—	—	✓	
CMK	2002-15699	1/02	JP	—	—	✓	

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